Welcome Message
from the General Co-Chairs
and Program Co-Chairs

Throughout the last years, on-line testing techniques have attracted an increasing interest from any application field because of their ability to detect both permanent and transient faults within an electronic component, thus allowing to minimize, if not eliminate, their produced effects. With the prospected dramatic increase of the likelihood of temporary as well as permanent faults for nanotechnology electronic systems, and with their increasing adoption in many safety-critical applications, it is not surprising that on-line testing techniques are experiencing today such an increasing interest!

During the same recent years, the IEEE International On-Line Testing Workshop became a recognized forum where those working in the field meet to share ideas and experiences. Due to its stable and increasing audience and quality of technical contributions, the workshop has been elevated to the 9th IEEE International On-Line Testing Symposium (IOLTS) 2003. The Program Committee had a hard job to select 33 papers and 14 posters. Thanks to the regular paper sessions, the invited talks, and the panels, we hope that the attendees will find the program technically stimulating.

Once more, this year the Symposium will be held in a nice Mediterranean island, Kos Island, Greece. Thanks to the work of the organizers, the attendees will be in the best position to discuss technical issues in a charming and relaxing environment.

Welcome to the 9th IEEE International On-Line Testing Symposium!

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